

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter		Rating		Unit
			N-Channel	P-Channel	
V _{DSS}	Drain-Source Voltage		20	-20	V
V _{GSS}	Gate-Source Voltage		±12	±12	
I _D *	Continuous Drain Current	V _{GS} =±4.5V	3	-2	A
I _{DM} *	300μs Pulsed Drain Current		12	-8	
I _S *	Diode Continuous Forward Current		1	-1	A
T _J	Maximum Junction Temperature		150		°C
T _{STG}	Storage Temperature Range		-55 to 150		
P _D *	Power Dissipation	T _A =25°C	0.83		W
		T _A =100°C	0.3		
R _{θJA} *	Thermal Resistance-Junction to Ambient		150		°C/W

Note : *Surface Mounted on 1in² pad area, $t \leq 10\text{sec}$.

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	APM2701AC			Unit	
			Min.	Typ.	Max.		
Static Characteristics							
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	N-Ch	20	-	-	V
		V _{GS} =0V, I _{DS} =-250μA	P-Ch	-20	-	-	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =16V, V _{GS} =0V T _J =85°C	N-Ch	-	-	1	μA
				-	-	30	
		V _{DS} =-16V, V _{GS} =0V T _J =85°C	P-Ch	-	-	-1	
				-	-	-30	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	N-Ch	0.5	0.7	1	V
		V _{DS} =V _{GS} , I _{DS} =-250μA	P-Ch	-0.5	-0.7	-1	
I _{GSS}	Gate Leakage Current	V _{GS} =±10V, V _{DS} =0V	N-Ch	-	-	±10	μA
			P-Ch	-	-	±10	
R _{DS(ON)} ^a	Drain-Source On-State Resistance	V _{GS} =4.5V, I _{DS} =3A	N-Ch	-	50	65	mΩ
		V _{GS} =-4.5V, I _{DS} =-2A	P-Ch	-	90	120	
		V _{GS} =2.5V, I _{DS} =1.7A	N-Ch	-	65	90	
		V _{GS} =-2.5V, I _{DS} =-1A	P-Ch	-	130	180	

Electrical Characteristics (Cont.) ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	APM2701AC			Unit	
			Min.	Typ.	Max.		
Diode Characteristics							
V_{SD}^a	Diode Forward Voltage	$I_{SD}=0.5A, V_{GS}=0V$	N-Ch	-	0.7	1.3	V
		$I_{SD}=-0.5A, V_{GS}=0V$	P-Ch	-	-0.7	-1.3	
t_{rr}	Reverse Recovery Time	N-Channel $I_{SD}=3A,$ $dI_{SD}/dt=100A/\mu s$	N-Ch	-	11	-	ns
			P-Ch	-	12	-	
Q_{rr}	Reverse Recovery Charge	P-Channel $I_{SD}=-2A,$ $dI_{SD}/dt=100A/\mu s$	N-Ch	-	4	-	nC
			P-Ch	-	4	-	
Dynamic Characteristics ^b							
C_{iss}	Input Capacitance	N-Channel $V_{GS}=0V,$ $V_{DS}=10V,$ Frequency=1.0MHz	N-Ch	-	300	-	pF
			P-Ch	-	375	-	
C_{oss}	Output Capacitance	P-Channel $V_{GS}=0V,$ $V_{DS}=-10V,$ Frequency=1.0MHz	N-Ch	-	70	-	
			P-Ch	-	70	-	
C_{rss}	Reverse Transfer Capacitance		N-Ch	-	50	-	
			P-Ch	-	50	-	
$t_{d(ON)}$	Turn-on Delay Time	N-Channel $V_{DD}=10V, R_L=10\Omega,$ $I_{DS}=1A, V_{GEN}=4.5V,$ $R_G=6\Omega$	N-Ch	-	4	8	ns
			P-Ch	-	6	12	
T_r	Turn-on Rise Time		N-Ch	-	14	26	
			P-Ch	-	14	26	
$t_{d(OFF)}$	Turn-off Delay Time	P-Channel $V_{DD}=-10V, R_L=10\Omega,$ $I_{DS}=-1A, V_{GEN}=-4.5V,$ $R_G=6\Omega$	N-Ch	-	21	39	
			P-Ch	-	27	50	
T_f	Turn-off Fall Time		N-Ch	-	5	10	
			P-Ch	-	5	10	
Gate Charge Characteristics ^b							
Q_g	Total Gate Charge	N-Channel $V_{DS}=10V, V_{GS}=4.5V,$ $I_{DS}=3A$	N-Ch	-	4.1	6	nC
			P-Ch	-	4.2	6	
Q_{gs}	Gate-Source Charge	P-Channel $V_{DS}=-10V, V_{GS}=-4.5V,$ $I_{DS}=-2A$	N-Ch	-	0.4	-	
			P-Ch	-	0.6	-	
Q_{gd}	Gate-Drain Charge		N-Ch	-	1.7	-	
			P-Ch	-	1.3	-	

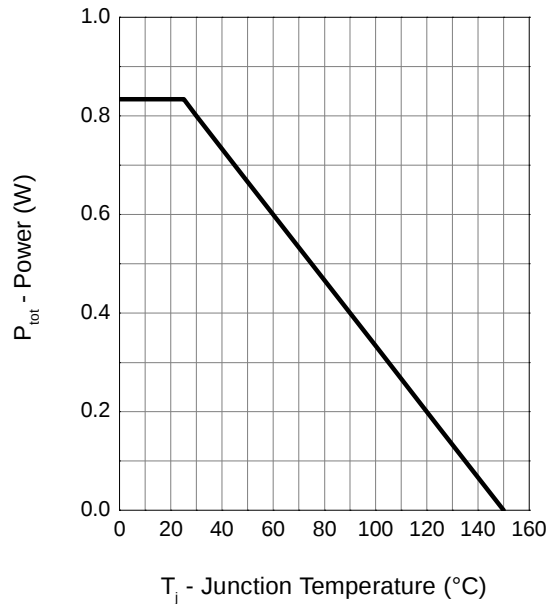
Note a : Pulse test ; pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

Note b : Guaranteed by design, not subject to production testing.

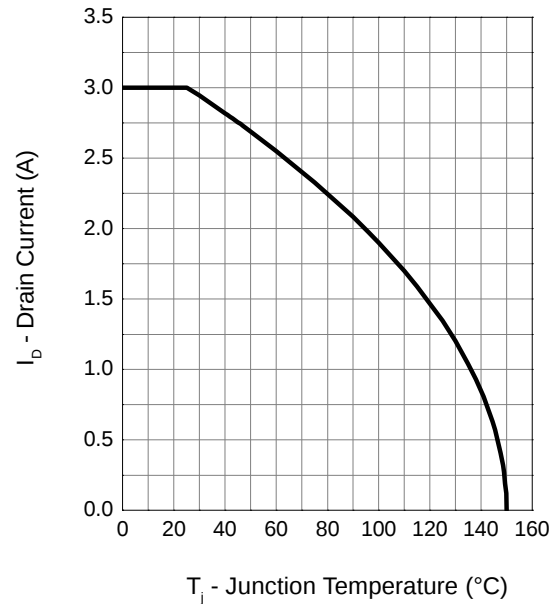
Typical Operating Characteristics

N-Channel

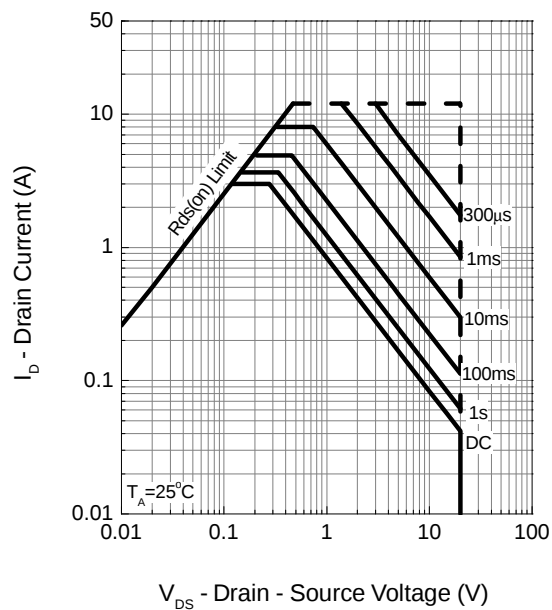
Power Dissipation



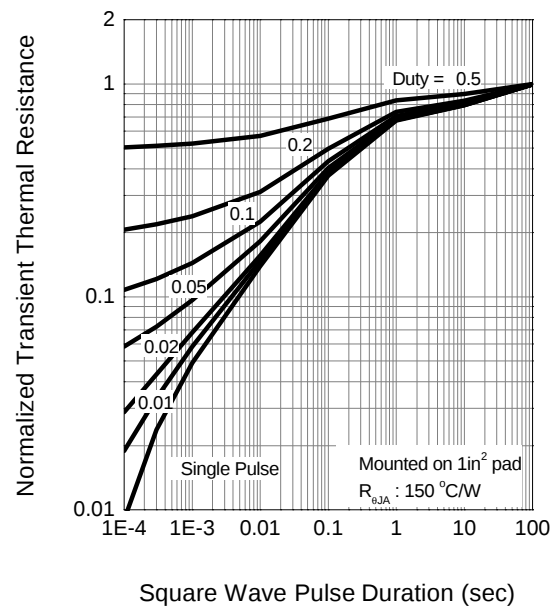
Drain Current



Safe Operation Area

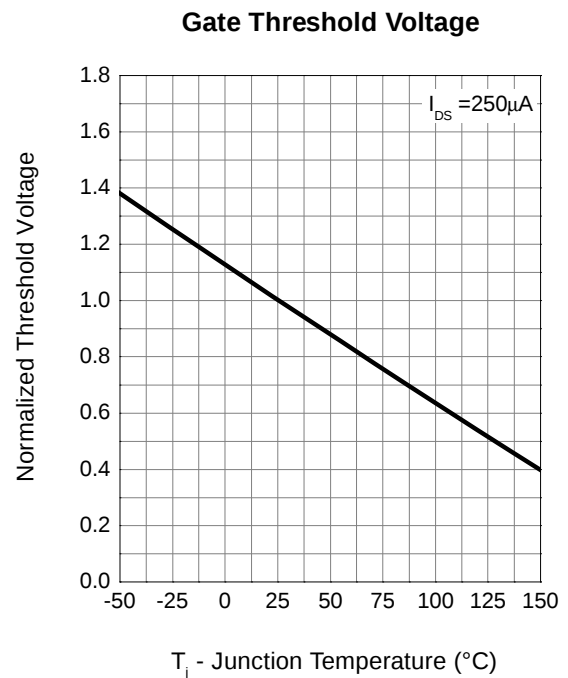
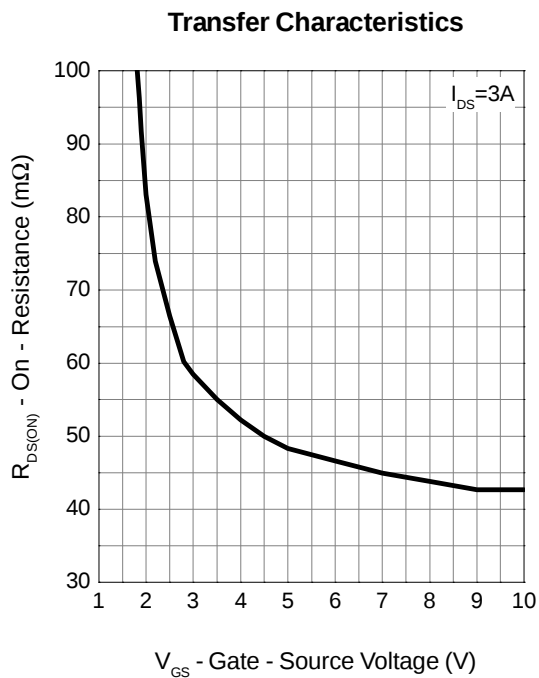
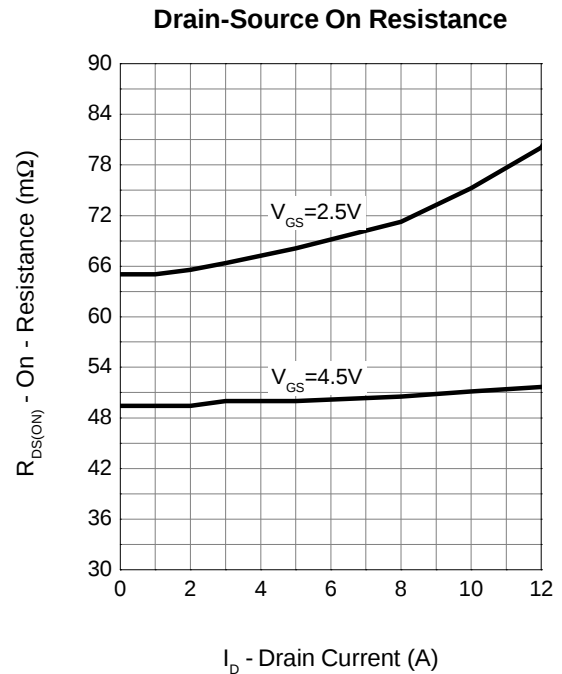
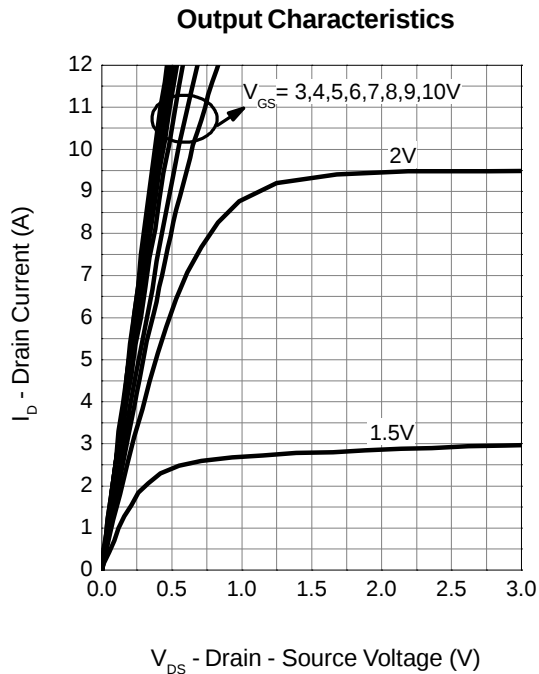


Thermal Transient Impedance



Typical Operating Characteristics (Cont.)

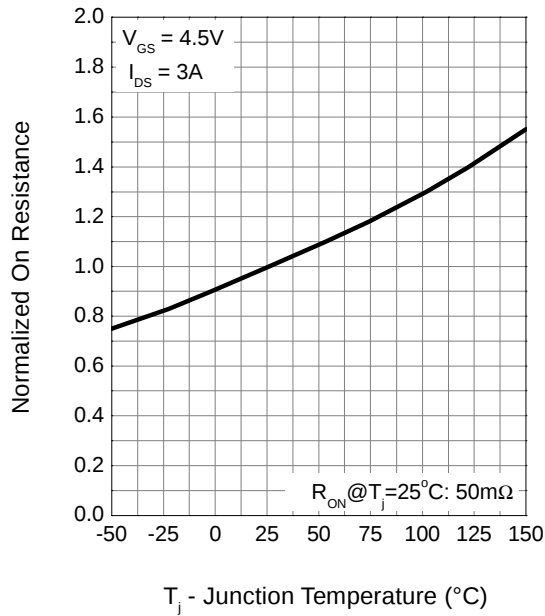
N-Channel



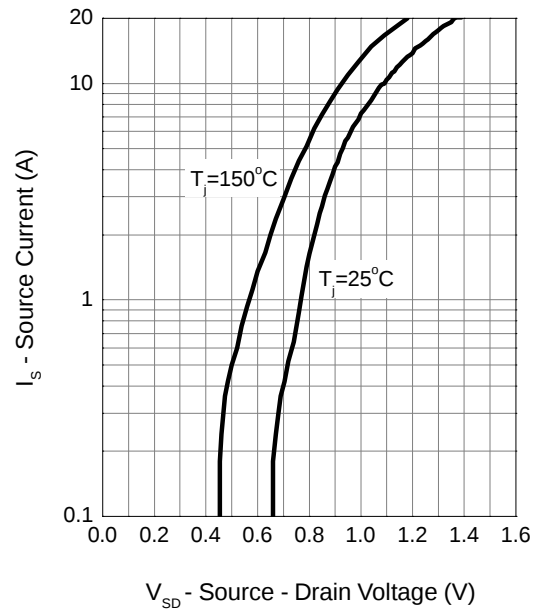
Typical Operating Characteristics (Cont.)

N-Channel

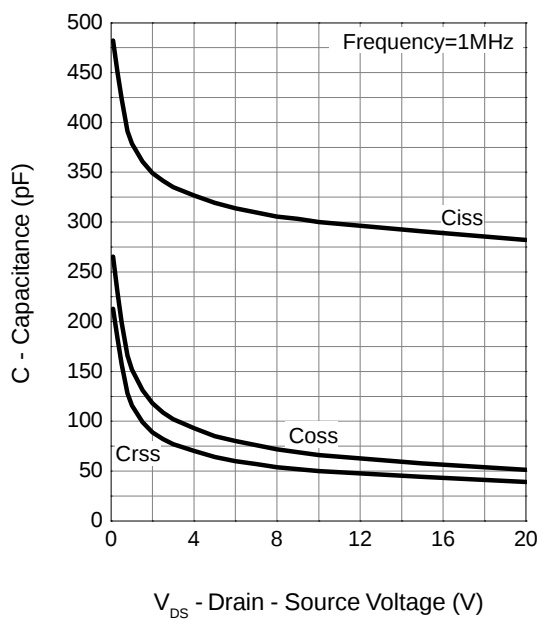
Drain-Source On Resistance



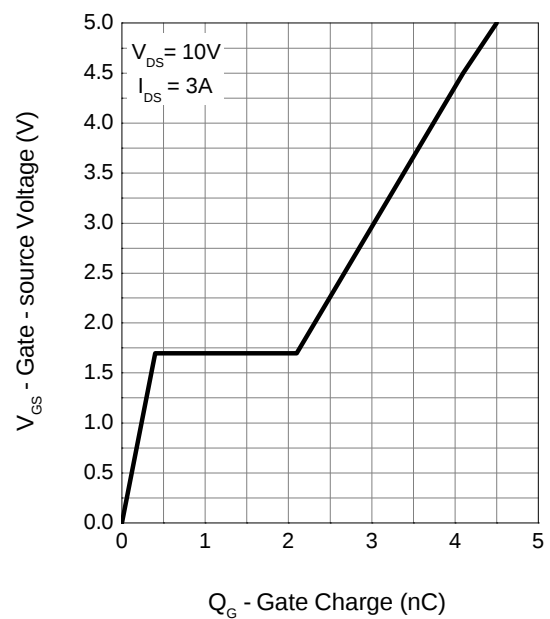
Source-Drain Diode Forward



Capacitance



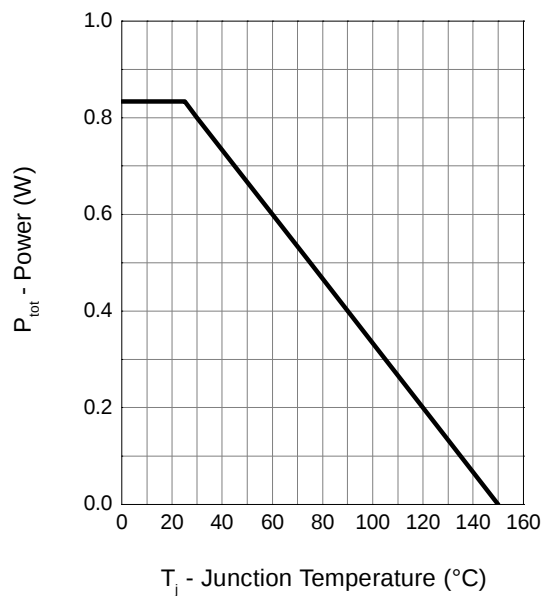
Gate Charge



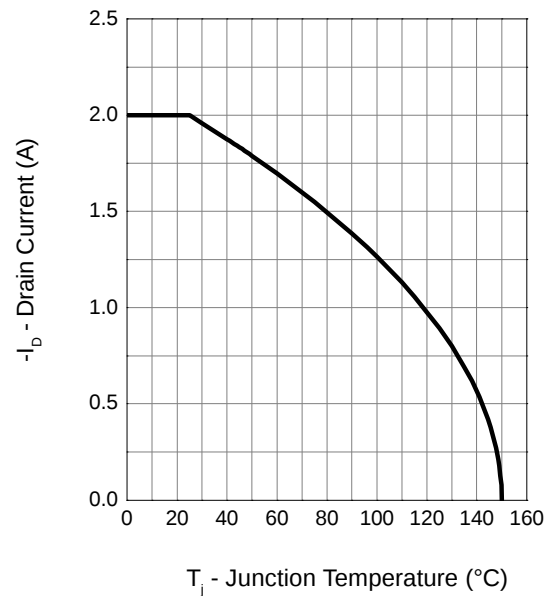
Typical Operating Characteristics (Cont.)

P-Channel

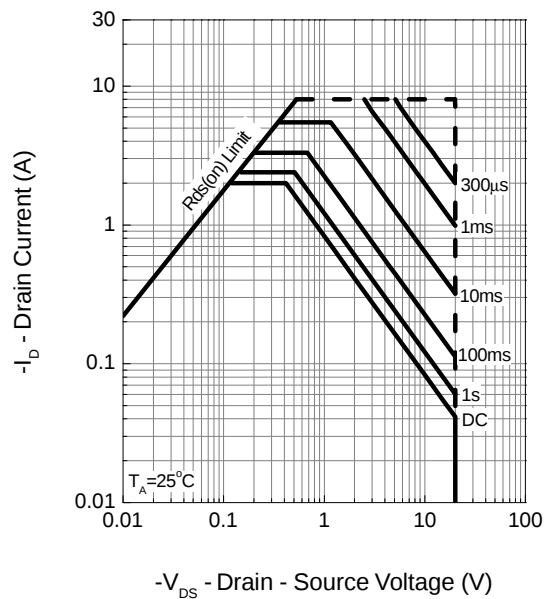
Power Dissipation



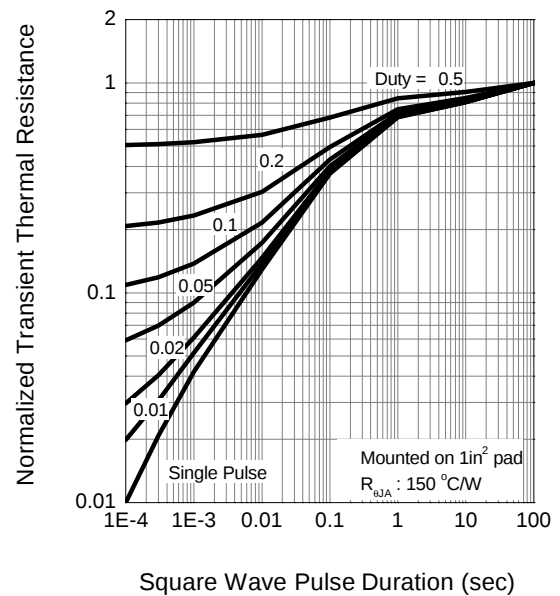
Drain Current



Safe Operation Area



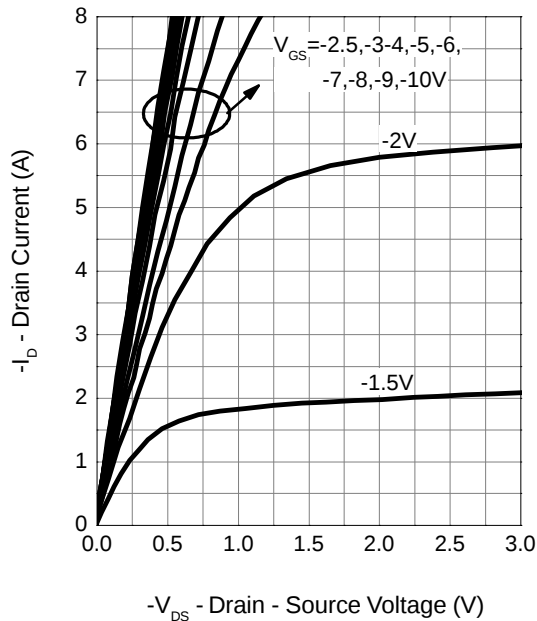
Thermal Transient Impedance



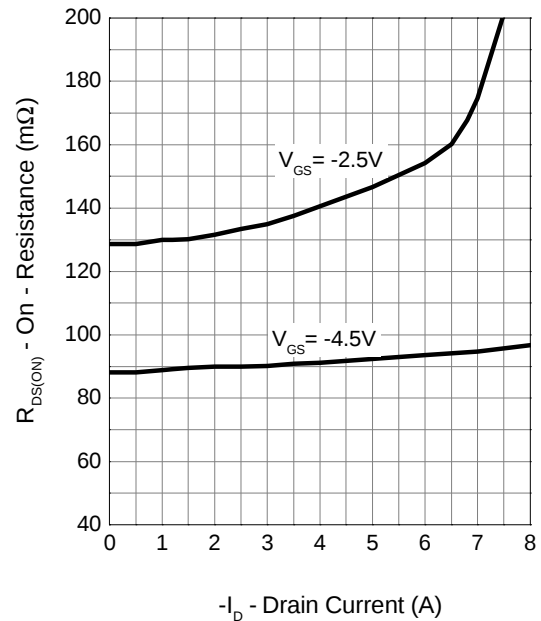
Typical Operating Characteristics (Cont.)

P-Channel

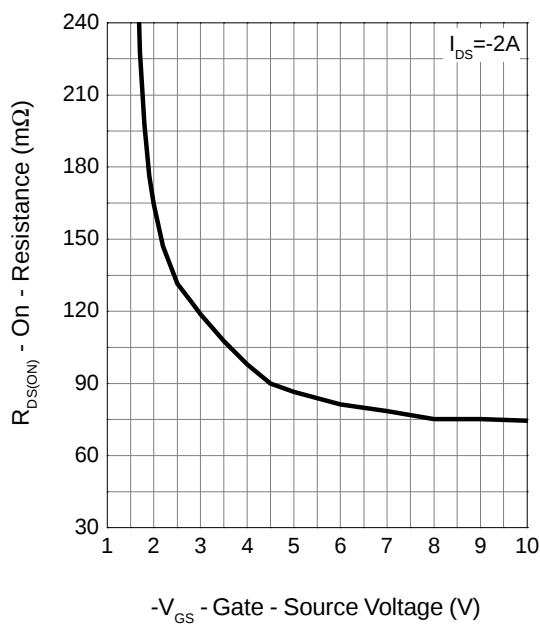
Output Characteristics



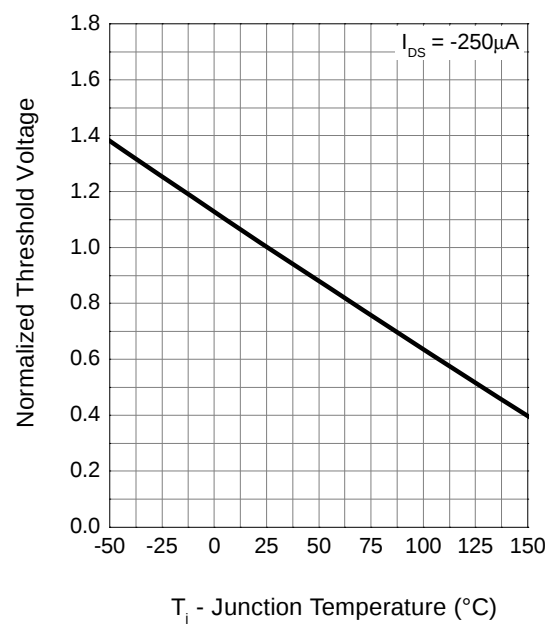
Drain-Source On Resistance



Transfer Characteristics



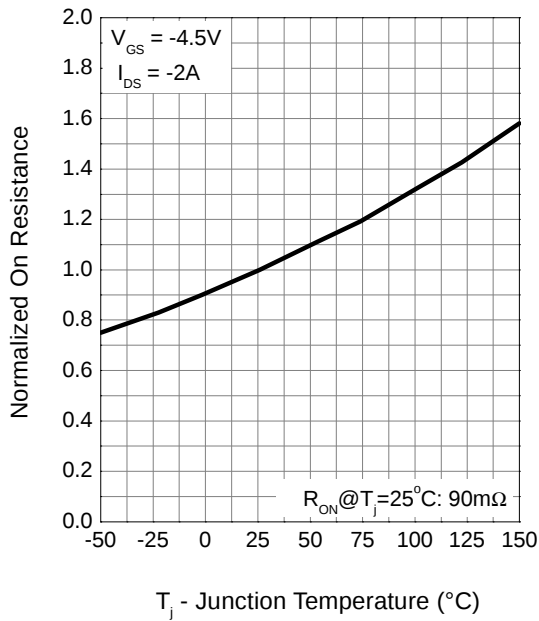
Gate Threshold Voltage



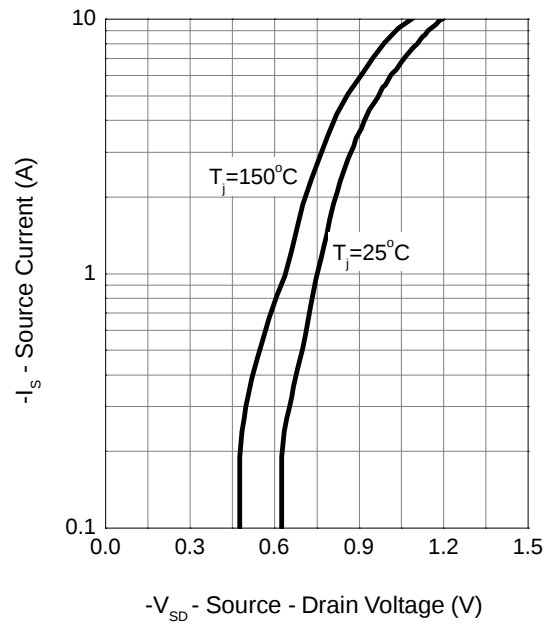
Typical Operating Characteristics (Cont.)

P-Channel

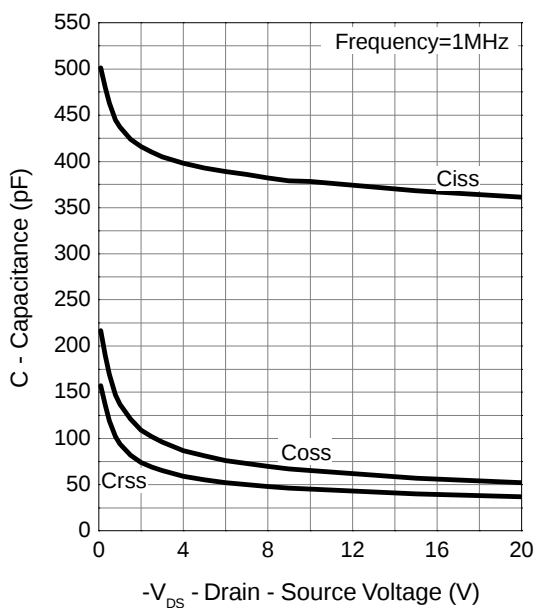
Drain-Source On Resistance



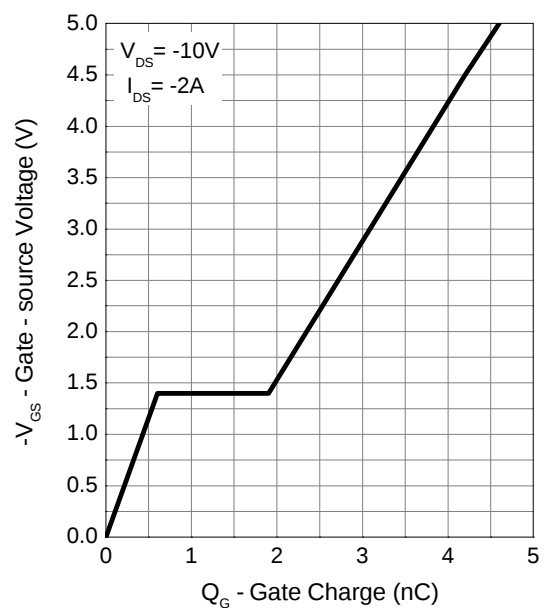
Source-Drain Diode Forward



Capacitance

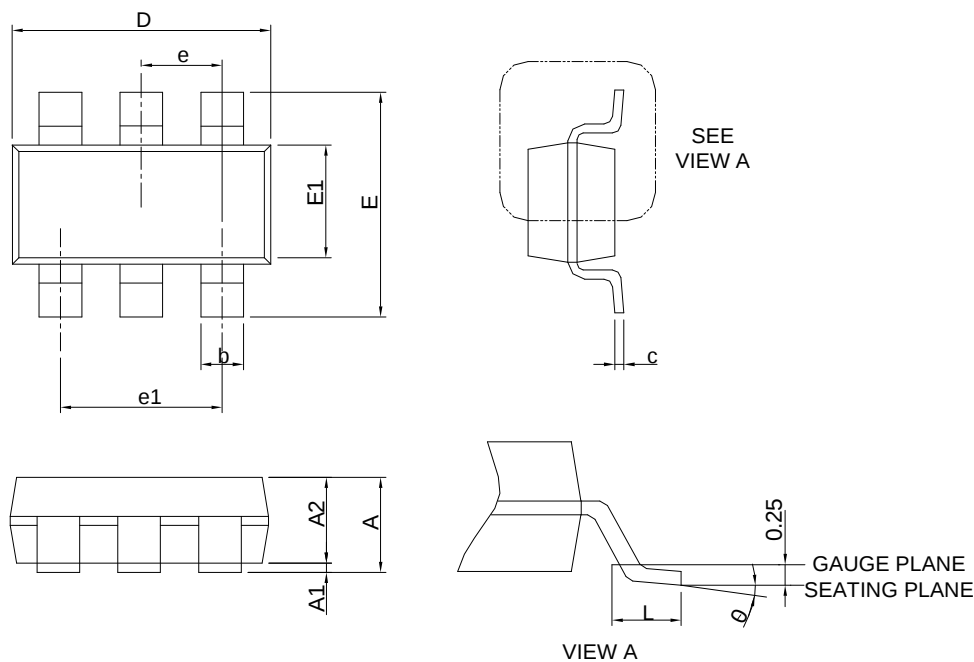


Gate Charge



Package Information

SOT-23-6

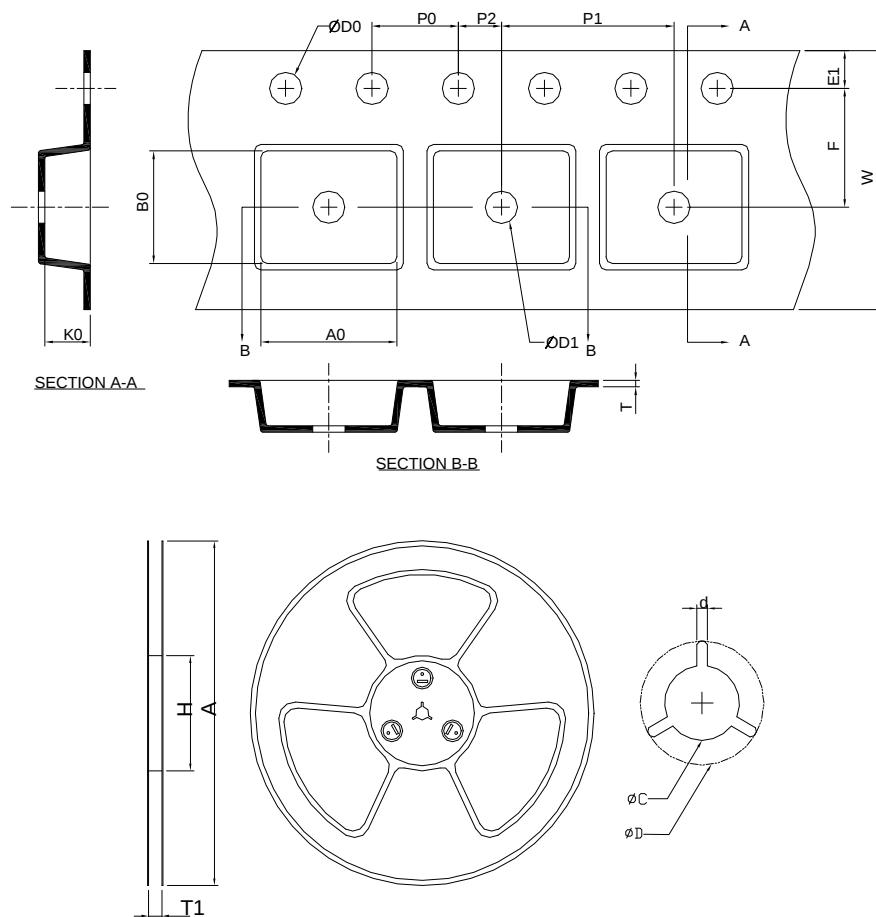


SYMBOL	SOT-23-6			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A		1.45		0.057
A1	0.00	0.15	0.000	0.006
A2	0.90	1.30	0.035	0.051
b	0.30	0.50	0.012	0.020
c	0.08	0.22	0.003	0.009
D	2.70	3.10	0.106	0.122
E	2.60	3.00	0.102	0.118
E1	1.40	1.80	0.055	0.071
e	0.95 BSC		0.037 BSC	
e1	1.90 BSC		0.075 BSC	
L	0.30	0.60	0.012	0.024
θ	0°	8°	0°	8°

Note : 1. Follow JEDEC TO-178 AB.

2. Dimension D and E1 do not include mold flash, protrusions or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 10 mil per side.

Carrier Tape & Reel Dimensions



Application	A	H	T1	C	d	D	W	E1	F
SOT-23-6	178.0 $\pm$ 0.00	50 MIN.	8.4+2.00 -0.00	13.0+0.50 -0.20	1.5 MIN.	20.2 MIN.	8.0 $\pm$ 0.30	1.75 $\pm$ 0.10	3.5 $\pm$ 0.05
	P0	P1	P2	D0	D1	T	A0	B0	K0
	4.0 $\pm$ 0.10	4.0 $\pm$ 0.10	2.0 $\pm$ 0.05	1.5+0.10 -0.00	1.0 MIN.	0.6+0.00 -0.40	3.20 $\pm$ 0.20	3.10 $\pm$ 0.20	1.50 $\pm$ 0.20

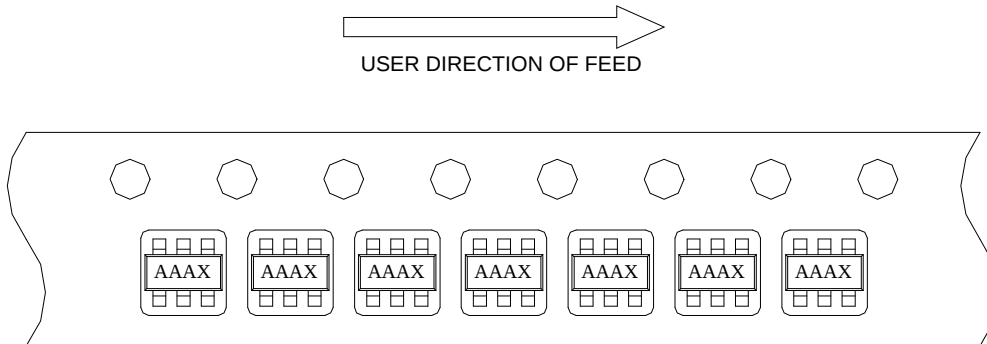
(mm)

Devices Per Unit

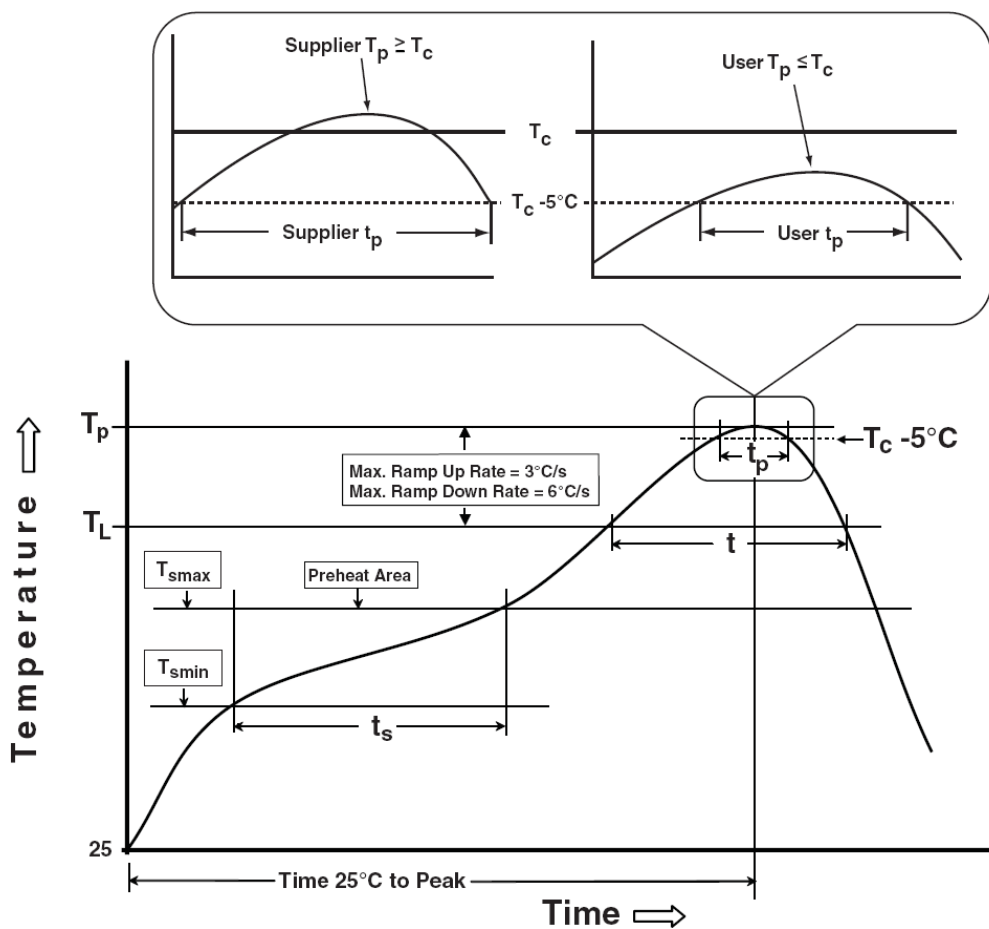
Package Type	Unit	Quantity
SOT-23-6	Tape & Reel	3000

Taping Direction Information

SOT-23-6



Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T_{smin}) Temperature max (T_{smax}) Time (T_{smin} to T_{smax}) (t_s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L) Time at liquidous (t_L)	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum. ** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HOLT	JESD-22, A108	1000 Hrs, Bias @ 125°C
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

Customer Service

Anpec Electronics Corp.

Head Office :

No.6, Dusing 1st Road, SBIP,

Hsin-Chu, Taiwan, R.O.C.

Tel : 886-3-5642000

Fax : 886-3-5642050

Taipei Branch :

2F, No. 11, Lane 218, Sec 2 Jhongsing Rd.,

Sindain City, Taipei County 23146, Taiwan

Tel : 886-2-2910-3838

Fax : 886-2-2917-3838